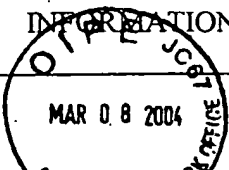







Date: March 8, 2004

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FORM PTO-1449 (Colb)	ATTY DOCKET NO. 22350/21	SERIAL NUMBER 10/689,314
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT David BERMAN, et al.	EXAMINER AA Kao
	FILING DATE October 20, 2003	GROUP ART UNIT AA 2882






U.S. PATENT DOCUMENTS


Examiner's initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
	AA	5,740,226	Apr. 1998	Komiya, et al.			
	AB	5,619,548	Apr. 1997	Koppel			
	AC	5,923,720	Jul. 1999	Barton, et al.			
	AD	6,512,814	01-2003	Yokhin, et al.			
	AE	2001/0043668	11-2001	Hayashi, et al.			

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	AG	Chihab et al., "New Apparatus for Grazing X-Ray Reflectometry in the Angle-Resolved Dispersive Mode", Journal of Applied Crystallography 22 (1989), p. 460.
	AH	XTF5011 Tube, Produced by Oxford Instruments of Scotts Valley, California. June 1999.
	AI	Doubly-Bent Focusing Crystal Optic, Produced by XOS Inc., of Albany, New York. July 2000.
	AJ	Wiener et al., "Characterization of Titanium Nitride Layers by Grazing-Emission X-Ray Fluorescence Spectrometry", in Applied Surface Science 125 (1998), pp. 129-136.
	AK	Model S7032-0908N array, Produced by Hamamatsu, of Hamamatsu City, Japan. May 2000.

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	AA	2001/0028699	10-2001	Iwasaki			
	AB	6,381,303	04-2002	Vu, et al.			
	AC	6,389,102	05-2002	Mazor, et al.			
	AD	5,574,284	11-1996	Farr			
	AE	5,151,588	09-1992	Kiri, et al.			
	AF	4,725,963	02-1988	Taylor, et al.			

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	AB	5,619,548	Apr. 1997	Koppel			
	AC	5,923,720	Jul. 1999	Barton, et al.			
	AD	6,512,814	01-2003	Yokhin, et al.			
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AC	6,389,102	05-2002	Mazor, et al.				
AD	5,574,284	11-1996	Fan				
AE	5,151,588	09-1992	Kiri, et al.				
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	FILING DATE October 20, 2003	GROUP ART UNIT (N/A) 2882

U.S. PATENT DOCUMENTS

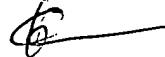
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	FILING DATE October 20, 2003	GROUP ART UNIT 2882

U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
<i>K</i>	AA	6,744,950	06-2004	Aleksoff			
	AB	6,643,354	11-2003	Koppel, et al.			
	AC	6,507,634	01-2003	Koppel, et al.			
	AD	6,453,006	09-2002	Koppel, et al.			
	AE	2004/0052330	03-2004	Koppel, et al.			
	AF	2002/0110218	08-2002	Koppel, et al.			
	AG	2002/0097837	07-2002	Fanton, et al.			
<i>K</i>	AH	6,711,232	03-2004	Janik			

FOREIGN PATENT DOCUMENTS

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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT David BERMAN, et al.	EXAMINER (N/A) K90
	FILING DATE October 20, 2003	GROUP ART UNIT 2882

U.S. PATENT DOCUMENTS

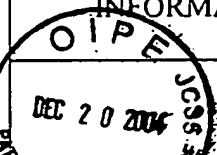
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<i>[initials]</i>	AA	6,771,735	08-2004	Janik, et al.			
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	AC	6,192,103	02-2001	Wormington, et al.			
<i>[initials]</i>	AD	5,949,847	09-1999	Terada, et al.			
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






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	AA	2004/0218717	11-2004	Koppel, et al.			
	AB	6,813,338	11-2004	Takata, et al.			
	AC						

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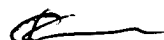
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